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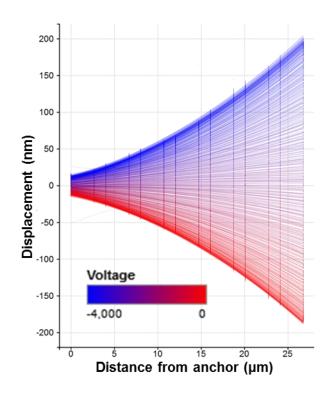


Figure S1 The out of plane displacement measured on a number of locations close to the anchor is plotted as points, and the quadratic regression fit used to extract the curvature is superimposed as a line segment connecting the points.

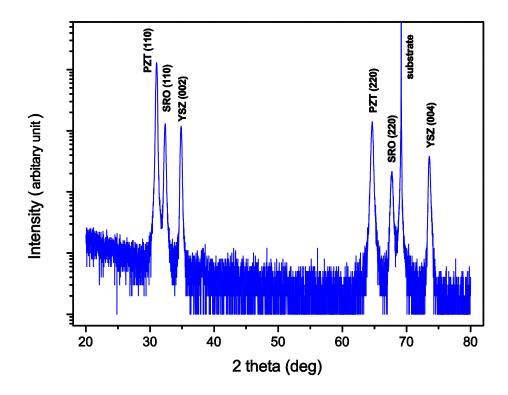


Figure S2 X-Ray diffraction pattern of the perovskite heterostructures.

Thickness of film (nm)	Position of 2 theta PZT (110) (deg)	Position of 2 theta PZT (220) (deg)	d ₍₀₁₁₎ (nm)
75	30.995	64.752	0.2886
100	31.055	64.5368	0.2877
150	31.065	64.32	0.2876

Supplementary Table 1. Peak positions and calculated atomic spacing of the (011) planes.